

SPECIFICATION FOR APPROVAL

CUSTOMER : _____

PRODUCT TYPE : SMD LVPECL VCXO 3.2*2.5

NOMINAL FREQ. : 122.88MHz

TXC P/N : DJA2200001

REVISION : S2

CUSTOMER P/N : _____

PM / SALES : _____

DATE : _____

CUSTOMER CONFIRMATION : _____
(Singnature)

_____ (Date)

- (1) TXC requires one copy returned with signature and title of authorized individual that signifies acceptance of the attached specifications.
- (2) Orders received and accepted by TXC after return of signed copy of specification will be produced per these specifications.
- (3) Any changes to these specifications must be agreed upon by both parties and new revision of the Product Specification Sheet will be issued.
- (4) Any issuance of purchase order prior to consigning back the Approval page of "Specification Sheets" from customers will be regarded as the agreement on the contents of these specifications.

MSL:Level 1
RoHS Compliant

(for glass crystal only : Pb used in sealing glass material is exempt from EU directive)

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| PE/RD | QA | ME |
|------------|----|----|
| Oscar Chen | | |
| 2017/10/30 | | |

NOTE:

- (1) The green product standard set by TXC is based upon the international standards. Related information is publicly described on the TXC's Website, and updated regularly. The document is compliant with the latest green product quality system directives at the time.
- (2) Revision "Sx" is for engineering samples only. PE/RD's approval required.
- (3) Revision "Ax" is production ready. PE, QA and MFG's approval required.

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RoHS Compliant

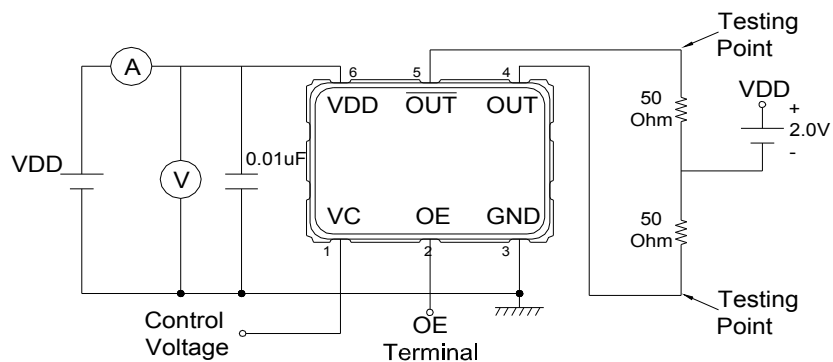
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ELECTRICAL SPECIFICATIONS

| Item | Parameters | Condition | Electrical Specifications | | | |
|------|--|---------------------------|---------------------------|-----------|-----------|---------|
| | | | MIN | TYP | MAX | UNITS |
| 1 | Nominal Frequency | | 122.880000 | | | MHz |
| 2 | Oscillation Mode | | Fundamental | | | |
| 3 | Operating Temperature | | -40 | - | 105 | °C |
| 4 | Storage Temperature | | -55 | - | 125 | °C |
| 5 | Frequency Stability | Note 4 | - | - | ±50 | ppm |
| 6 | Supply Voltage | | 3.135 | 3.30 | 3.465 | V |
| 7 | Current Consumption | RL=50Ω to VDD-2V | - | 40 | 60 | mA |
| 8 | Standby Function | Internal Pull Up | YES | | | |
| 9 | Current Consumption(Standby) | OE=Low | - | - | 10 | mA |
| 10 | Output Type | | LVPECL | | | |
| 11 | Output Load | | 50 | | | Ω |
| 12 | Output Voltage High +25 °C | | VDD-1.025 | VDD-0.950 | VDD-0.880 | V |
| 13 | Output Voltage Low +25 °C | | VDD-1.810 | VDD-1.700 | VDD-1.620 | V |
| 14 | Rise Time | 20%~80% Output Swing | - | - | 0.5 | nS |
| 15 | Fall Time | 80%~20% Output Swing | - | - | 0.5 | nS |
| 16 | Symmetry or Duty Cycle | | 45 | 50 | 55 | % |
| 17 | Jitter(12kHz - 20MHz BW), 122.88MHz | | - | 0.13 | - | ps(rms) |
| 18 | Phase Noise, fo = 122.88MHz 10 Hz offset 100 Hz offset 1k Hz offset 10k Hz offset 100k Hz offset 1M Hz offset 10M Hz offset | | - | | | |
| | | | - | -67 | - | dBc/Hz |
| | | | - | -100 | - | dBc/Hz |
| | | | - | -125 | - | dBc/Hz |
| | | | - | -142 | - | dBc/Hz |
| | | | - | -153 | - | dBc/Hz |
| | | | - | -154 | - | dBc/Hz |
| | | | - | -156 | - | dBc/Hz |
| 19 | Start-up Time | To 90% of Final Amplitude | - | - | 10 | mS |
| 20 | Enable Voltage High (Logic 1) | Note 2 | 0.7VDD | - | VDD | V |
| 21 | Enable Voltage Low (Logic 0) | Note 2 | GND | - | 0.3VDD | V |
| 22 | Control Voltage | | 0 | 1.65 | 3.3 | V |
| 23 | Absolute Pulling Range (APR) | Note 1 | ±50 | - | - | ppm |
| 24 | Control Voltage Bandwidth | -3dB | 15 | - | - | kHz |
| 25 | VC Pin Input Impedance | | 5 | - | - | MΩ |
| 26 | Linearity | | - | - | 10 | % |

Note 1 APR=Pull Range - (frequency tolerance at 25°C, variation over temperature, supply voltage, and aging.)
 Note 2 Output will be enable if OE is Logic 1 or open ; Output will be disable if OE is Logic 0.
 Note 3 The standard testing environment except temperature test is 25±5°C, 40%~70% relative humidity.
 Note 4 Frequency tolerance at 25°C, variation over temperature, supply voltage, and aging.

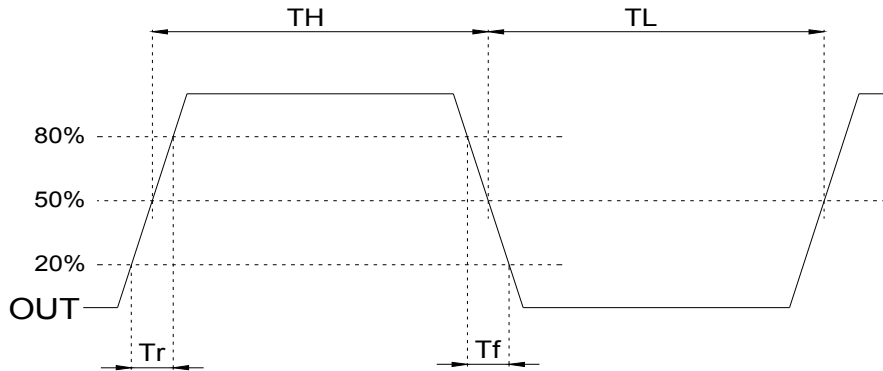
TESTING CIRCUIT



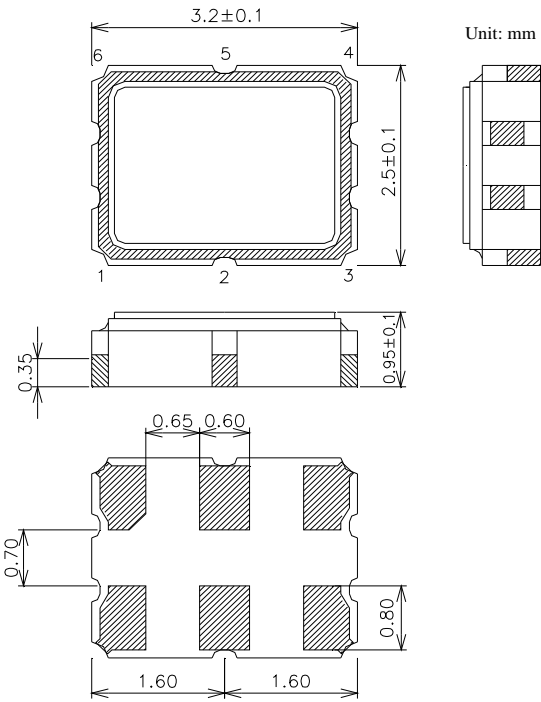
Testing Circuit Note:

- 1) Above testing circuits cover all the specifications except temperature test & Jitter measurement.
- 2) All the testing equipments are 50Ohm terminal.
- 3) OE terminal is open connection except OE function test.

WAVEFORM CONDITONS



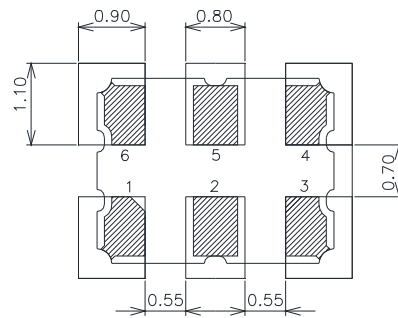
DIMENSIONS



Pin Function:

1. VC
2. OE
3. GND
4. OUT
5. $\overline{\text{OUT}}$
6. VDD

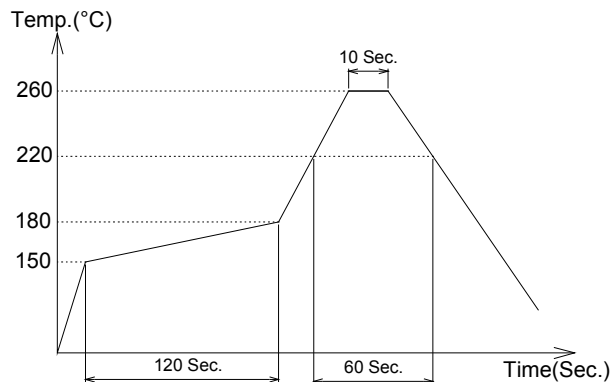
Land Pattern:



※ Pad dimension tolerance ± 0.2 mm

※ Power Supply Decoupling Capacitor is Required.

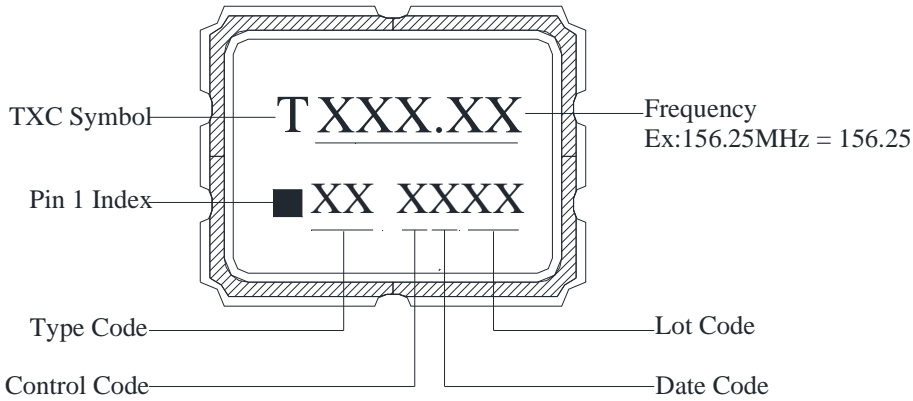
SUGGESTED REFLOW PROFILE



Note 1: Period while temperature exceeds the solder melting point : 220C should be less than 200 sec.

Note 2: Period while temperature stays at the top melting point : 260C should be less than 30 sec.

MARKING



DATE CODE

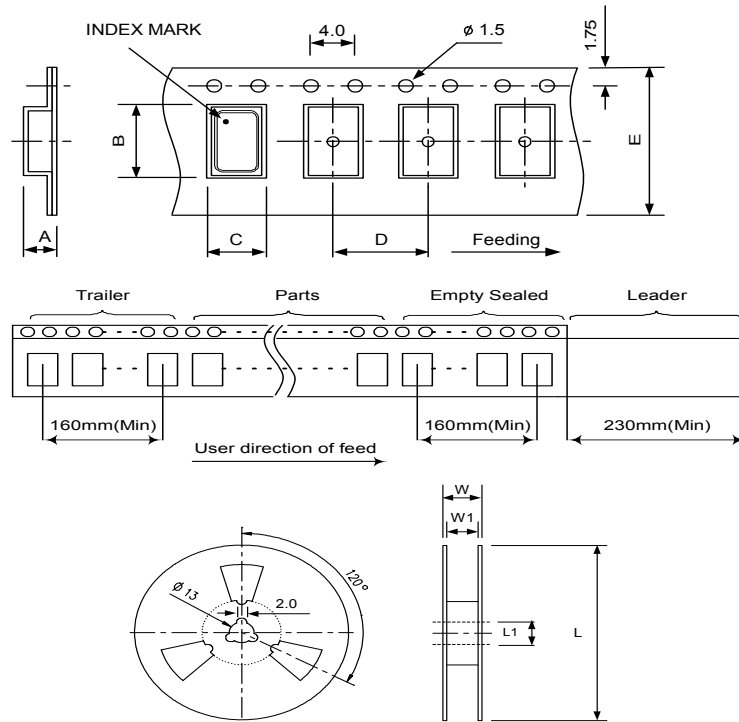
| YEAR | | | | | MONTH | | | | | | | | | | | |
|------|------|------|------|------|-------|-----|-----|-----|-----|-----|-----|-----|-----|-----|-----|-----|
| | | | | | JAN | FEB | MAR | APR | MAY | JUN | JUL | AUG | SEP | OCT | NOV | DEC |
| 2005 | 2009 | 2013 | 2017 | 2021 | A | B | C | D | E | F | G | H | J | K | L | M |
| 2006 | 2010 | 2014 | 2018 | 2022 | N | P | Q | R | S | T | U | V | W | X | Y | Z |
| 2007 | 2011 | 2015 | 2019 | 2023 | a | b | c | d | e | f | g | h | j | k | l | m |
| 2008 | 2012 | 2016 | 2020 | 2024 | n | p | q | r | s | t | u | v | w | x | y | z |

* This date code will be cycled every four years.

TYPE CODE

| Oscillation mode | Fundamental | PLL | Multiplier |
|------------------|-------------|-----|------------|
| Code | DJ | - | - |

PACKING : (EIA-481-2)



Unit: mm

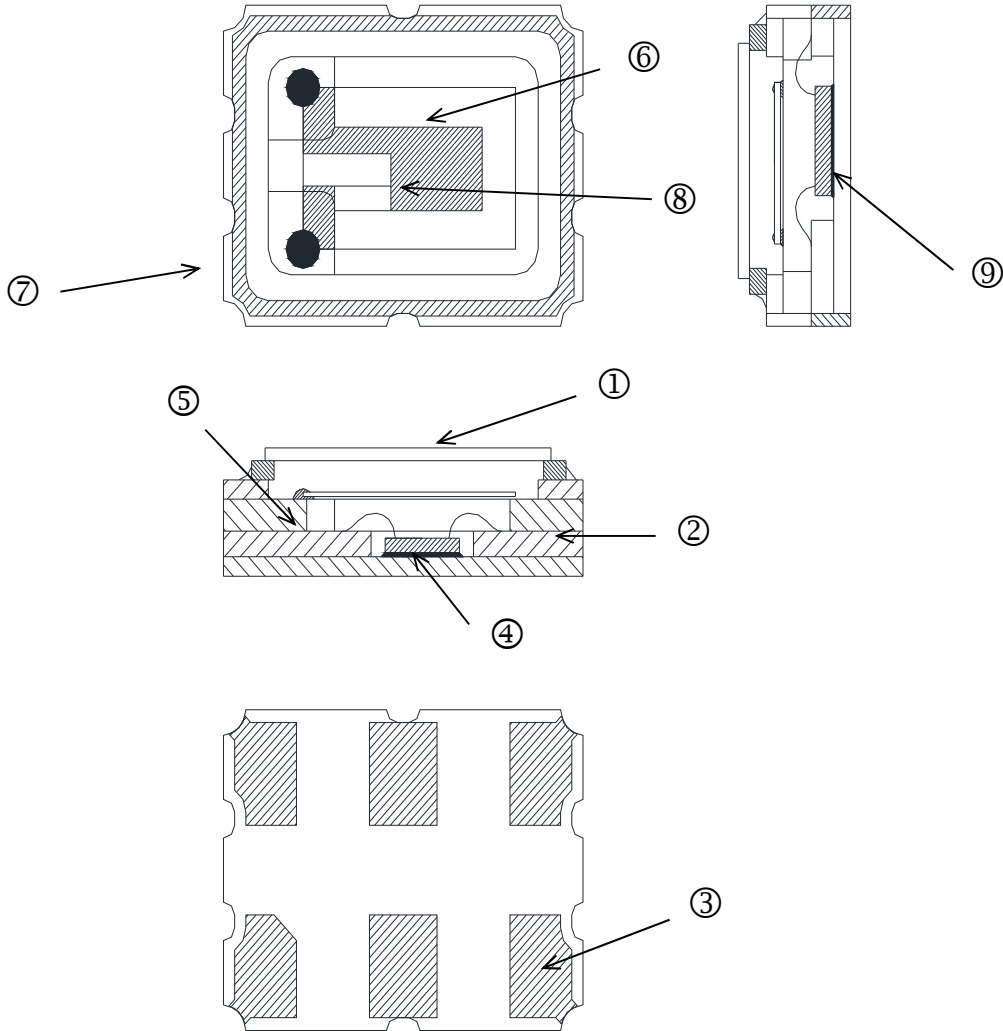
| DIMENSIONS (mm) | A | B | C | D | E | L | L1 | W | W1 | Standard Reel Quantity is 3,000 pcs per reel |
|-----------------|------|------|------|------|-----|-------|------|------|-----|--|
| | 1.40 | 3.40 | 2.70 | 4.00 | 8.0 | 178.0 | 13.0 | 11.5 | 8.0 | |

WEIGHT

0.0217 g / piece(TYP), 65 ± 2 g / 3 kpcs (regardless of tape weight)

■ STRUCTURE ILLUSTRATION

Crystal Enclosure Seal: Seam Welding
 Crystal Enclosure Medium: Vacuum



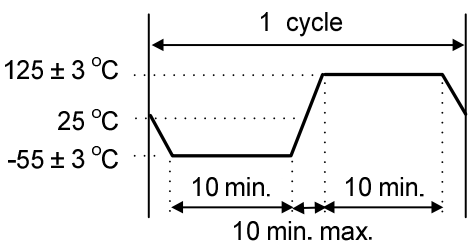
| No. | COMPONENTS | MATERIALS | FINISH/SPECIFICATIONS |
|-----|---------------------|---|---|
| 1 | Lid | Kovar(Fe-Ni-Co) | - |
| 2 | Base(Package) | Ceramic (Al ₂ O ₃) | - |
| 3 | Pad | Au | Tungsten Metalize + Ni Plating + Au Plating |
| 4 | IC Chip | Si | - |
| 5 | Bonding Wire | Au | - |
| 6 | Crystal Blank | SiO ₂ | - |
| 7 | Conductive Adhesive | Ag | Silicon Resin |
| 8 | Electrode | Noble metal | - |
| 9 | Conductive Adhesive | Ag | Epoxy Resin |

RELIABILITY SPECIFICATIONS

1. Mechanical Endurance

| No. | Test Item | Test Methods | REF. DOC |
|-----|------------------|---|--------------|
| 1.1 | Drop Test | 75 cm height, fall freely onto concrete floor 3 times. | JIS C6701 |
| 1.2 | Mechanical Shock | Devices are shocked to half sine wave (1000 G) three mutually perpendicular axis each 3 times. 0.5m sec. duration time. | MIL-STD-202F |
| 1.3 | Vibration | Frequency range 10 ~ 2000 Hz Amplitude 1.52 mm Sweep time 20 minutes Perpendicular axis each test 4 hours (Total test time 12 hrs) | MIL-STD-883E |
| 1.4 | Gross Leak | Standard sample for automatic gross leak detector. Test Pressure: 2Kg / cm ² | MIL-STD-883E |
| 1.5 | Fine Leak | Pre-condition - Helium bombing 4.5 Kgf / cm ² for 2 hrs Tested by mass-spectrometer | MIL-STD-883E |
| 1.6 | Solderability | Temperature 245 °C ± 5°C Immersing depth 0.5 mm minimum Immersion time 5 ± 1 seconds Flux Rosin resin methyl alcohol solvent (1 : 4) | MIL-STD-883E |

2. Environmental Endurance

| No. | Test Item | Test Methods | REF. DOC |
|-----|------------------------------|---|--------------|
| 2.1 | Resistance to Soldering Heat | Pre-heat temperature 125 °C Pre-heat time 60 ~ 120 sec. Test temperature 260 ± 5 °C Test time 10 ± 1 sec. | MIL-STD-202F |
| 2.2 | High Temp. Storage | +125 °C ± 3 °C for 1000 hours | MIL-STD-883E |
| 2.3 | Low Temp. Storage | -40 °C ± 3 °C for 1000 hours | |
| 2.4 | Thermal Shock (Air to Air) | Total 100 cycles of the following temperature cycle  | MIL-STD-883E |
| 2.5 | Pressure Cooker Test | 120 ± 3°C, RH100%, 2 bar, for 240 hours | EIA-JESD22 |
| 2.6 | High Temp. & Humidity | 85°C ± 3°C, RH 85% , 1000 hours | EIA-JESD22 |
| 2.7 | Aging | 85°C ± 3°C, Voltage input by specification, 1000 hours | EIA-JESD22 |